

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
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Examiner		Art Unit		Page 1 of 1
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*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B US-2004/0058269	03-2004	Hada et al.	430/270.1
C	US-			
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E	US-			
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

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N	WO 03/048863	06-2003		Hada, H. et al.	
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NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
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